



FORM PTO/SB/08A/B (10-01)
Substitute for PTO-1449A/B

INFORMATION DISCLOSURE

STATEMENT BY APPLICANT

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Attorney Docket Number

45129/RAG/C766

Application Number

09/927,779

Filing Date

August 9, 2001

Applicant(s)

Michael L. Roukes, et al.

Group Art Unit

1641

Examiner Name

Ann Y. Lam

U.S. PATENT DOCUMENTS

EXAMINER INITIALS	Cite No. ¹	DOCUMENT NUMBER Number - Kind Code ² (If Known)	PUBLICATION DATE MM-DD-YYYY	NAME OF PATENTEE
OP		5,282,924	02-01-1994	Bayer, et al.
OP		5,807,758	09-15-1998	Lee, et al.

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OP		WO 98/50773	11-12-1998	Charych, et al.	
OP		WO 00/58729	10-05-2000	Thundat, et al.	
OP		WO 01/33226 A1	05-10-2001	Baller, et al.	

OTHER DOCUMENTS

EXAMINER INITIALS	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article, title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.
OP		Supplemental European Search Report dated June 15, 2004, European Patent Application No. 01964587
OP		BASELT, David R., et al., "Biosensor based on force microscope technology", J. Vac. Sci. Technol. B 14(2), Mar/Apr 1996, pgs. 789-793; XP000613363
OP		LANG, H.P., et al., "An artificial nose based on a micromechanical cantilever array", Analytica Chimica Acta, Vol. 393, March 1999, pgs. 59-65; XP000990018
OP		FRITZ, J, et al., "Translating Biomolecular Recognition into Nanomechanics", Science, 14 April 2000, pgs. 316-319, Vol. 288; XP000971747

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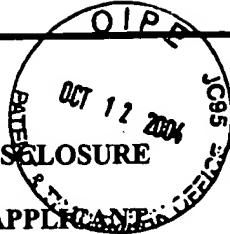
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Cite
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[Signature]

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[Signature]

CRAIGHEAD, H.G., "Nanoelectromechanical Systems", Science, 24 November 2000, pgs. 1532-1535, Vol. 290; XP000941737

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Applicant(s)	Michael L. Roukes, et al.
Group Art Unit	2881 164
Examiner Name	Not Yet Determined LAM

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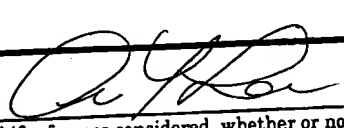
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		PCT International Preliminary Examination Report dated April 22, 2003 from corresponding International Application No. PCT/US01/41645 filed August 9, 2001

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Applicant(s)	Michael L. Roukes, et al.
Group Art Unit	2881 1641
Examiner Name	to be assigned LAM

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AL		PCT International Search Report dated February 21, 2002 from corresponding PCT application No. PCT/US01/41645 filed August 9, 2001

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Application Number 09/927,779

Filing Date August 9, 2001

Applicant(s) Michael L. Roukes, et al.

Group Art Unit 2881/64/

Examiner Name To be Assigned

U.S. PATENT DOCUMENTS

EXAMINER INITIALS	DOCUMENT NUMBER	ISSUE DATE	PATENTEE	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

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						YES	NO

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CHUI	CHUI, B.W., et al., "Independent detection of vertical and lateral forces with a sidewall-implanted dual-axis piezoresistive cantilever", Appl. Phys. Lett., 16 March 1998, pgs. 1388-1390, Vol. 72, No. 11, American Institute of Physics.
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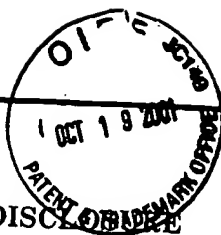
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<i>CP</i>	WHALEN, Anthony D., "Detection of Signals in Noise", Chapter 1. Probability, 1971, pgs. 1-26, Academic Press, New York.

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